

10/663,741.

Docket No.: M4065.0656/P656

(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Letters Patent of:

Terry L. Gilton

Patent No.: 6,903,361

Issued: June 7, 2005

of Correction

For: NON-VOLATILE MEMORY STRUCTURE

REQUEST FOR CERTIFICATE OF CORRECTION PURSUANT TO 37 CFR 1.322 & 1.323

Attention: Certificate of Correction Branch

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Dear Sir:

Upon reviewing the above-identified patent, Patentee noted typographical errors which should be corrected.

In the Drawings, Applicant's Submission of Formal Drawings, dated December 18, 2003, was not included in the printed patent by the PTO. Exhibit A (attached) is a copy of that Submission with drawings to be substituted for the rough drawings that are used in the patent.

In the U.S. Patent Documents portion of the References Cited section, the following is to be corrected:

2002/0000668 A1 1/2002 Kozicki et al. should read

2002/0000666 A1 1/2002 Kozicki et al.

In the Specification, Applicant made the following errors to be corrected:

Column 5:

Line 48, "deposition an" should read --deposition of an--; and

Line 61, "increase" should read --increases--.

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Line 47, "include" should read --includes--.

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Claim 25, line 2, "chacogenide" should read --chalcogenide--;

Claim 26, line 4, "chacogenide" should read --chalcogenide--; and

Claim 27, line 8, "tantalium" should read --tantalum--.

In the Other Publications portion of the References Cited section, the PTO made the following errors to be corrected:

"Yoji Kawamoto et al., "Ionic Conduction in As₂S₃-Ag₂S, GeS₂-GeS₂-GeS-AG₂S and P₂S₈-Ag₂S Glasses," Journal of Non-Crystalline Solids 20 (1976) 393-404."

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"El Bouchairi, B.; Bernede, J.C.; Burgaud, P., Propeties of Ag_{2-x}Se_{1+x/n}-Si diodes, Thin Solid Films 110 (1983) 107-113."

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"Mitokova, M.; Wang, Y.; Boolchand, P., Dual chemical role of Ag as an additive in chalcogenide glasses, Phys. Rev. Lett. 83 (1999) 3848-3851."

Should read

--Mitkova, M.; Wang, Y.; Boolchand, P., Dual chemical role of Ag as an additive in chalcogenide glasses, Phys. Rev. Lett. 83 (1999) 3848-3851.--.

Also in Other Publications, Applicant made the following errors to be corrected:

"Kotkata, M.F.; Afif, M.A.; Labib, H.H.; Hegab, N.A.; Abdel-Aziz, M.M., Memory switching in amorphous GeSeTl chalcogenide semiconductor films, Thin Solid Films 240 (1994) 143-146."

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"McHardy, et al., The dissolution of metals in amorphous chalcogenides and the effect o electrons and ultraviolet radiation, 20 J. Phys. C.: Solid State Phys., pp. 4055-4075 (1987)f."

Should read

--McHardy, et al., The dissolution of metals in amorphous chalcogenides and the effect of electrons and ultraviolet radiation, 20 J. Phys. C.: Solid State Phys., pp. 4055-4075 (1987).--.

The errors were both found in the application as filed by Applicant and made by the PTO. Please charge our Credit Card in the amount of \$100.00 covering the fee set forth in 37 CFR 1.20(a). Credit Card Payment Form SB-2038, with a signature from an authorized cardholder, is enclosed.

The errors now sought to be corrected are inadvertent typographical errors the correction of which does not involve new matter or require reexamination.

Transmitted herewith is a proposed Certificate of Correction effecting such amendment. Patentee respectfully solicits the granting of the requested Certificate of Correction.

The Director is hereby authorized to charge any deficiency in the fees filed, asserted to be filed or which should have been filed herewith (or with any paper hereafter filed in this application by this firm) to our Deposit Account No. 04-1073, under Order No. M4065.0656/P656.

Dated: December 14, 2006

Respectfully submitted,

Thomas J. D'Amico

Registration No.: 28,371

Elizabeth Parsons

Registration No.: 52,499

DICKSTEIN SHAPIRO LLP

1825 Eye Street, NW

Washington, DC 20006-5403

(202) 420-2200

Attorneys for Applicant

PTO/SB/17 (07-06)

Approved for use through 01/31/2007. OMB 0651-0032
U.S. Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE
der the Paperwork Reduction Act of 1995, no person are required to respond to a collection of information unless it displays a valid OMB control number. Complete if Known Effective on 12/08/2004. pursuant to the Consolidated Appropriations Act, 2005 (H.R. 4818). Patent#: 6,903,361 Application Number TRANSMITTAL Issued: June 7, 2005 Filing Date First Named Inventor Terry L. Gilton For FY 2006 Examiner Name C. Q. Nguyen Applicant claims small entity status. See 37 CFR 1.27 2811 Art Unit TOTAL AMOUNT OF PAYMENT M4065.0656/P656 100.00 Attorney Docket No. METHOD OF PAYMENT (check all that apply) Check x Credit Card Money Order None Other (please identify): Deposit Account Number: 04-1073 Deposit Account Name Dickstein Shapiro LLP For the above-identified deposit account, the Director is hereby authorized to: (check all that apply) Charge fee(s) indicated below Charge fee(s) indicated below, except for the filing fee Charge any additional fee(s) or underpayments of Credit any overpayments fee(s) under 37 CFR 1.16 and 1.17 **FEE CALCULATION** 1. BASIC FILING, SEARCH, AND EXAMINATION FEES **EXAMINATION FEES FILING FEES** SEARCH FEES Small Entity **Small Entity** Small Entity **Application Type** Fee (\$) Fee (\$) Fee (\$) Fee (\$) Fees Paid (\$) Fee (\$) Fee (\$) Utility 300 150 500 250 200 100 Design 200 100 100 50 130 65 Plant 200 100 300 150 160 80 Reissue 300 150 500 250 600 300 Provisional 200 100 0 0 O 0 2. EXCESS CLAIM FEES **Small Entity** Fee Description Fee (\$) Fee (\$) Each claim over 20 (including Reissues) 50 25 Each independent claim over 3 (including Reissues) 200 100 Multiple dependent claims 360 180 **Total Claims** Fee Paid (\$) **Extra Claims** Fee (\$) **Multiple Dependent Claims** Fee (\$) Fee Paid (\$) HP = highest number of total claims paid for, if greater than 20 Indep. Claims Fee Paid (\$) **Extra Claims** Fee (\$) HP = highest number of independent claims paid for, if greater than 3. 3. APPLICATION SIZE FEE

If the specification and drawings exceed 100 sheets of paper (excluding electronically filed sequence or computer listings under 37 CFR 1.52(e)), the application size fee due is \$250 (\$125 for small entity) for each additional 50 sheets or fraction thereof. See 35 U.S.C. 41(a)(1)(G) and 37 CFR 1.16(s).

	<u>Total Sheets</u>	Extra Sheets	<u>Nu</u>	mber of each additional 50 or fraction thereof	Fee (\$)		Fee Paid (\$)
	- 100) =	/50	(round up to a whole number) x		= _	
	4. OTHER FEE(S)						Fees Paid (\$)
	Non-English Specification, \$130 fee (no small entity discount)						
Other (e.g., late filing surcharge): 1811 Certificate of correction							100.00

SUBMITTED BY Registration No Signature 28,371 Telephone (202) 420-2232 (Attorney/Agent) Name (Print/Type) Thomas J. D'Amico Date December 14, 2006

Exhibit A

Atty Docket No.: M4065.0656/P656

Inventor: Terry L. Gilton

Application No.: 10/663,741

Title: NON-VOLATILE MEMORY STRUCTURE

Filing Date: September 17, 2003

Documents Filed:

Submission of Formal Drawings (1 page)

9 drawings (9 sheets)

Information Disclosure Statement (20 pages), PTO SB/08 (11 pages) with 1 box of references

Via: PTO DAILY RUN

Sender's Initials: TJD/CSC/cdl

Date: December 18, 2003

CAL 13-18-07



Docket No.: M4065.0656/P656

(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:

Terry L. Gilton

Application No.: 10/663,741

Filed: September 17, 2003

Art Unit: N/A

For: NON-VOLATILE MEMORY STRUCTURE

Examiner: Not Yet Assigned

SUBMISSION OF FORMAL DRAWINGS

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

Submitted herewith is one set (nine sheets, nine figures) of formal drawings for filing in the above-identified patent application. Kindly substitute the enclosed formal drawings for the informal drawings submitted with the originally filed application.

Dated: December 18, 2003

Respectfully sobmitted,

Thomas J. D'Amico

Registration No.: 28,371

Christopher S. Chow

Registration No.: 46,493

DICKSTEIN SHAPIRO MORIN &

OSHINSKY LLP

2101 L Street NW

Washington, DC 20037-1526

(202) 785-9700

Attorneys for Applicant



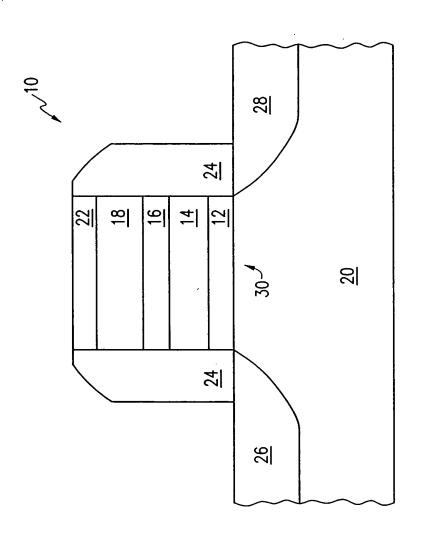


FIG. 1 (PRIOR ART)

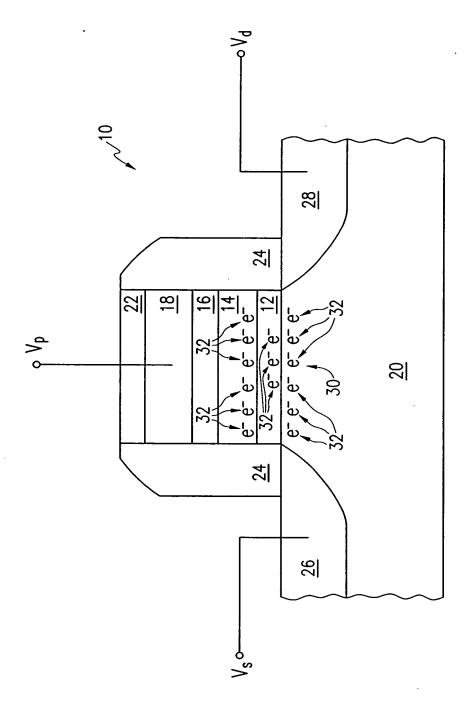
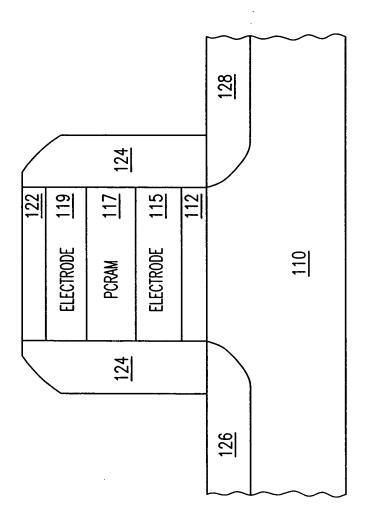
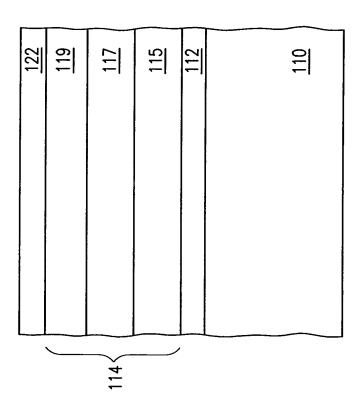


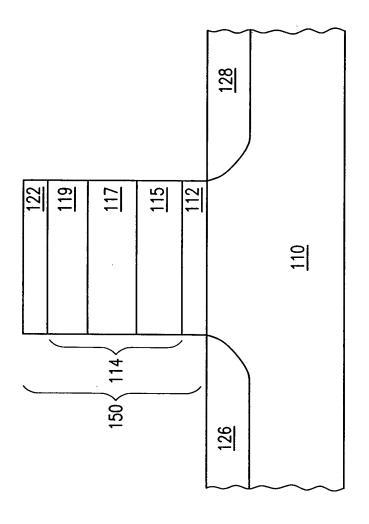
FIG. 2 (PRIOR ART)



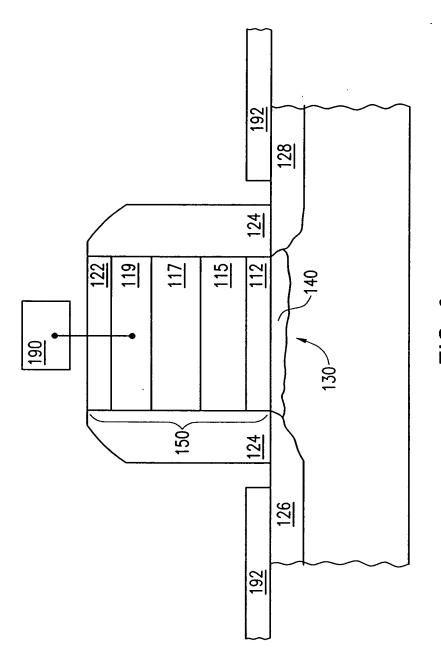
F/G. 3



F/G. 4



F/G. 5



F/G. 6

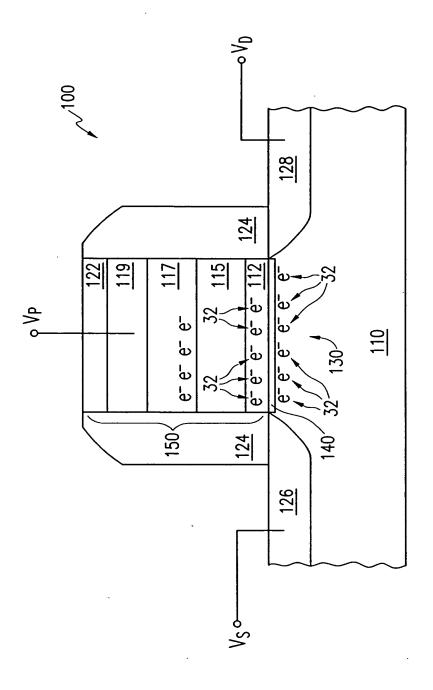
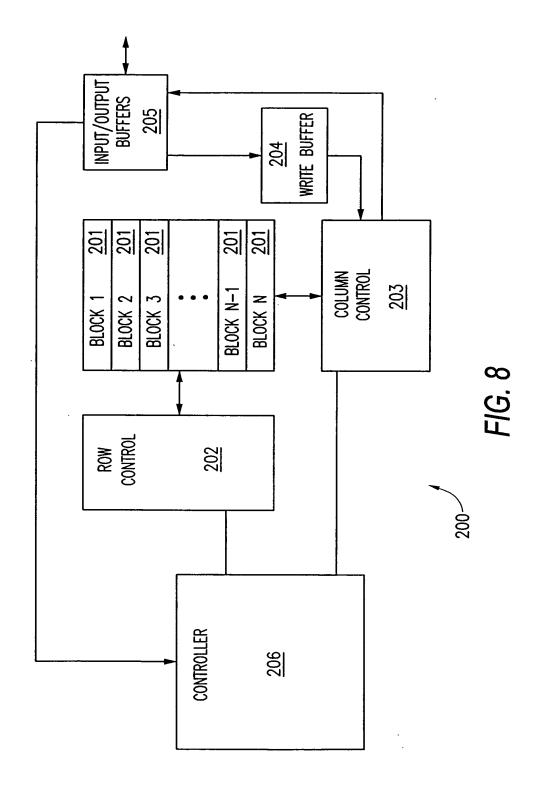
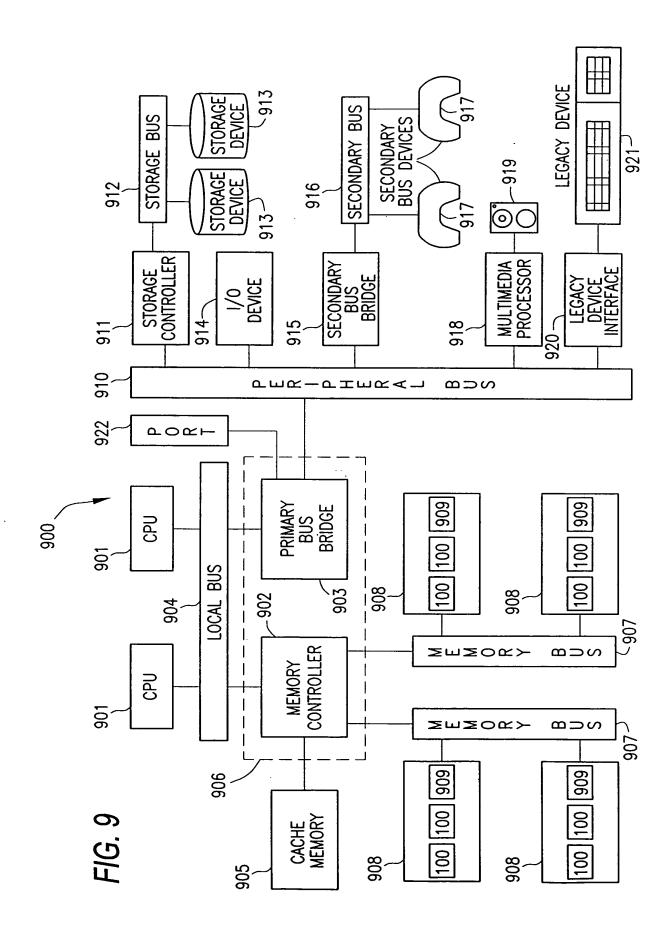


FIG. 7





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UNITED STATES PATENT AND TRADEMARK OFFICE CERTIFICATE OF CORRECTION

Page _1_ of _3_

PATENT NO.

6,903,361

APPLICATION NO. :

10/663,741

ISSUE DATE

June 7, 2005

INVENTOR

Terry L. Gilton

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MAILING ADDRESS OF SENDER (Please do not use customer number below): Thomas J. D'Amico DICKSTEIN SHAPIRO LLP 1825 Eye Street, NW Washington, DC 20006-5403

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Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it displays a valid OMB control number. (Also Form PTO-1050)

"Yoji Kawamoto et al., "Ionic Conduction in As₂S₃-Ag₂S, GeS₂-GeS₂-GeS-AG₂S and P₂S₂-Ag₂S Glasses," Journal of Non-Crystalline Solids 20 (1976) 393-404."

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Washington, DC 20006-5403

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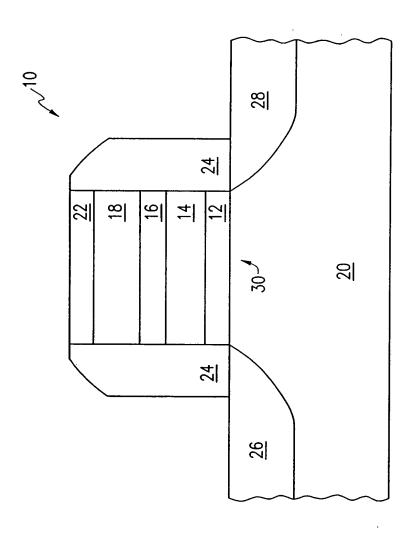
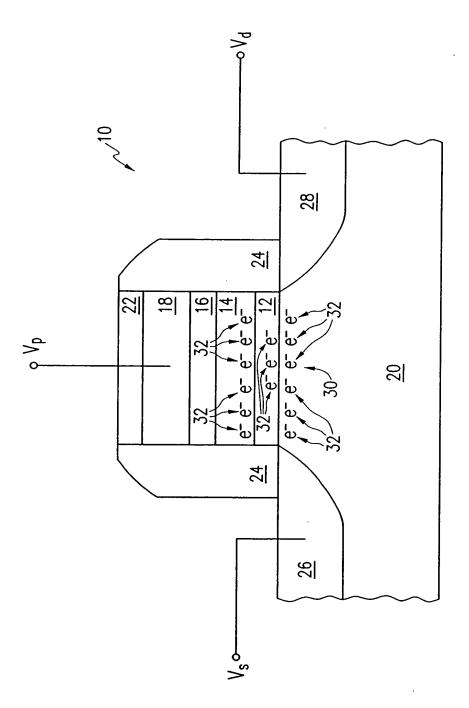
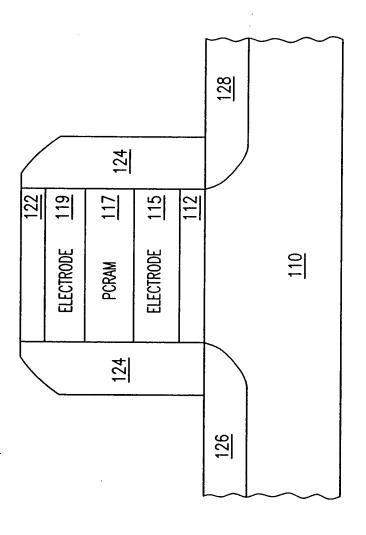


FIG. 1 (PRIOR ART)



1.5

FIG. 2 (PRIOR ART)



F/G. 3

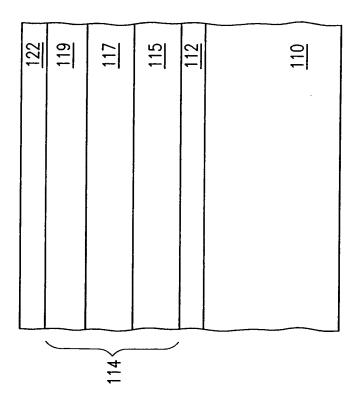


FIG. 4

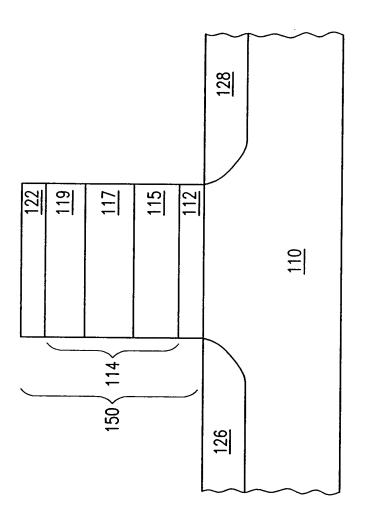
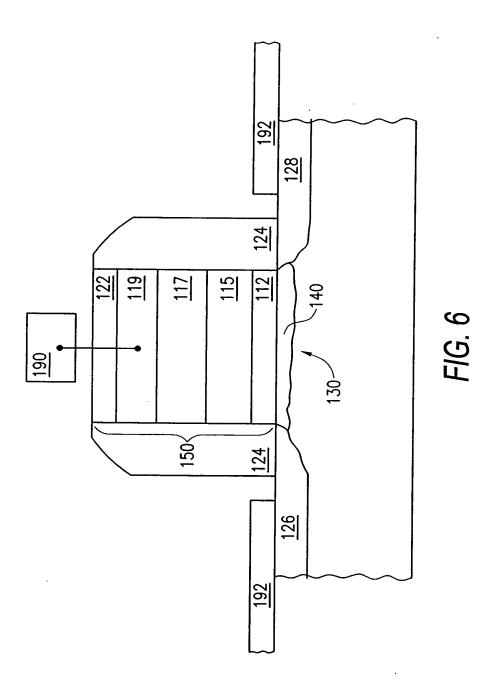


FIG. 5



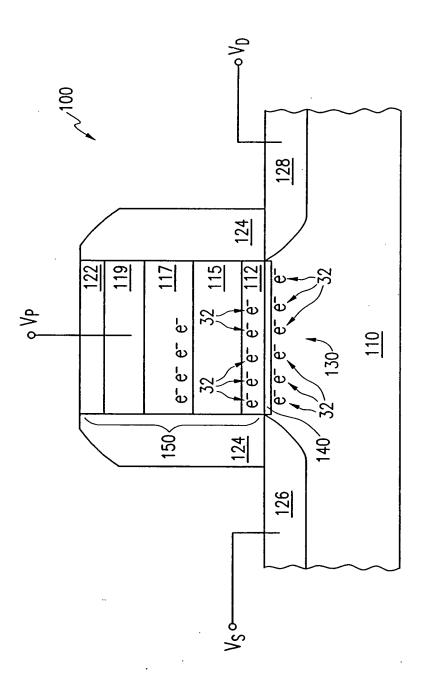
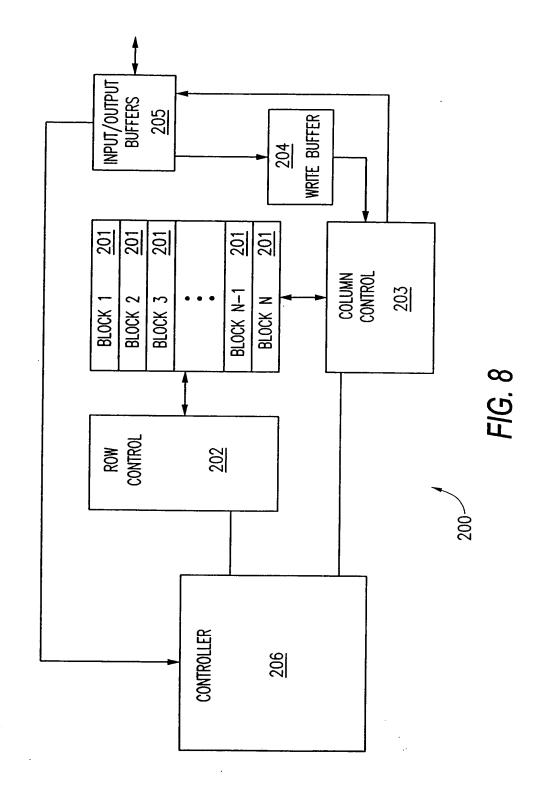
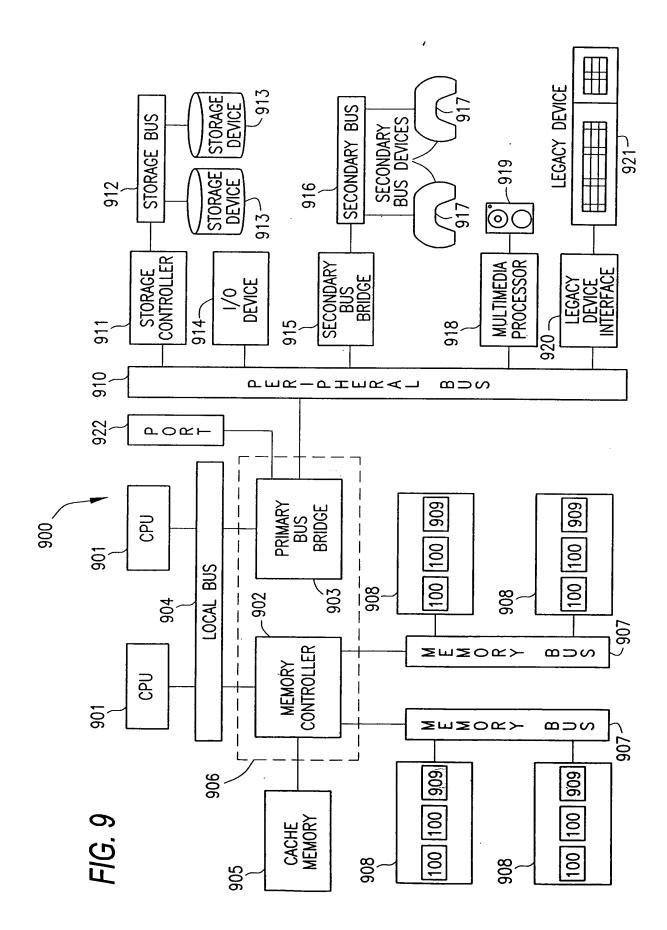


FIG. 7





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